

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/761,486	HARPER ET AL.	
Examiner		Art Unit		Page 1 of 1
Maria Veronica D. Ewald		1722		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,482,279	11-2002	Nakano et al.	156/73.1
*	B	US-5,571,473	11-1996	Fujii, Atsushi	264/510
*	C	US-6,793,476	09-2004	Bryja et al.	425/145
*	D	US-2003/0030188	02-2003	Spengler, Ernst Maximilian	264/458
*	E	US-6,482,742	11-2002	Chou, Stephen Y.	438/690
*	F	US-5,888,433	03-1999	Amo, Mikuni	264/1.33
*	G	US-2004/0238972	12-2004	Ho et al.	257/787
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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